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PATENTIN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	CIRKEL <i>et al.</i>	Examiner:	Vclez, R.
Serial No.:	10/527,569	Group Art Unit:	2829
Filed:	March 10, 2005	Docket No.:	NL020843 US
Title:	REDUCED CHIP TESTING SCHEME AT WAFER LEVEL		

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being transmitted via facsimile-Formal Entry, to the attention of the Examiner at Commissioner for Patents, MAIL STOP AMENDMENT, P.O. Box 1450, Alexandria, VA 22313-1450, on November 16, 2006.

By: 

Kelly J. Leatin

Facsimile No.: 571 273-8300

OFFICE ACTION RESPONSE AND AMENDMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Customer No.
24738

Dear Sir:

In response to the non-final Office Action dated August 21, 2006, please consider the following amendments and remarks.

A complete listing of the claims, to include any amendments presented therein, begins on page 2 of this paper.

Remarks/Arguments follow on page 4.

Authorization is provided to charge/credit Deposit Account 50-0996 (VLSI.503PA) any requisite fees/overages to enter this paper.